

BQ25960 I2C Controlled, Single Cell 8-A Switched Cap Parallel Battery Charger with Integrated Bypass Mode and Dual-Input Selector

1 Features

- 98.1% peak efficiency switched cap parallel charger supporting 8-A fast charge
- Patent pending dual phase switched cap architecture optimized for highest efficiency
	- Input voltage is 2x battery voltage
	- Output current is 2x of input current
- Reduces power loss across input cable
- Integrated 5-A Bypass Mode fast charge
	- $-$ 21-mΩ R_{dson} charging path resistance to support 5-A input and 5-A output charging current
- Dual-input power mux controller for source selection during fast charging and USB On-The-Go (OTG)/ reverse TX Mode
- Support wide range of input voltage
	- Up to 12.75-V operational input voltage
	- Maximum 40-V input voltage with optional external ACFET and 20-V without external ACFET
- Parallel charging with synchronized dual BQ25960 operations for up to 13-A charging current
- Integrated programmable protection features for safe operation
	- Input overvoltage protection (BUSOVP) and battery overvoltage protection (BATOVP)
	- Input overcurrent protection (BUSOCP) and battery overcurrent protection (BATOCP)
	- Output overvoltage protection (VOUTOVP)
	- Input undercurrent protection (BUSUCP) and input reverse-current protection (BUSRCP) to detect adapter unplug and prevent boost-back
	- Battery and connector temperature monitoring (TSBAT_FLT and TSBUS_FLT)
	- Junction overtemperature protection (TDIE_FLT)
- Programmable settings for system optimization
	- Interrupts and interrupt masks
	- ADC readings and configuration
	- Alarm functions for host control
- Integrated 16-bit ADC for voltage, current, and temperature monitoring

2 Applications

- **[Smartphone](https://www.ti.com/solution/smartphone)**
- **[Tablet](https://www.ti.com/applications/personal-electronics/tablets/overview.html)**

3 Description

The BQ25960 is a 98.1% peak efficiency, 8-A battery charging solution using switch capacitor architecture for 1-cell Li-ion battery. The switched cap architecture allows the cable current to be half the charging current, reducing the cable power loss, and limiting temperature rise. The dual-phase architecture increases charging efficiency and reduces the input and output cap requirements. When used with a main charger such as BQ2561x or BQ2589x, the system enables full charging cycle from trickle charge to termination with low power loss at Constant Current (CC) and Constant Voltage (CV) Mode.

The BQ25960 supports 5-A Bypass Mode charge (previously called battery switch charge) through internal MOSFETs. The R_{dson} in Bypass Mode charging path is 21 m Ω for high-current operation. The integrated Bypass Mode allows backward compatibility of 5-V fast charging adapter to charge 1 cell battery.

The device supports dual input configuration through integrated mux control and driver for external N-FETs. It also allows single input with no external N-FET or single N-FET.

Device Information

(1) For all available packages, see the orderable addendum at the end of the data sheet.

Simplified Schematic

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4 Revision History

5 Description (continued)

The device integrates all the necessary protection features to support safe charging, including input overvoltage and overcurrent protection, output overvoltage and overcurrent protection, input undercurrent and reversecurrent protection, temperature sensing for the battery and cable, and junction overtemperature protection in both Switched Cap and Bypass Mode.

The device includes a 16-bit analog-to-digital converter (ADC) to provide VAC voltage, bus voltage, bus current, output voltage, battery voltage, battery current, input connector temperature, battery temperature, junction temperature, and other calculated measurements needed to manage the charging of the battery from the adapter, or wireless input, or power bank.

6 Device Comparison Table

Table 6-1. Device Comparison

7 Pin Configuration and Functions

Figure 7-1. YBG Package - BQ25960 36-Pin DSBGA Top View

Table 7-1. Pin Functions

Table 7-1. Pin Functions (continued)

(1) Type: P = Power , AIO = Analog Input/Output , AI = Analog Input, DO = Digital Output, AO = Analog Output, DIO = Digital Input/Output

8 Specifications

8.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted) (1)

(1) Stresses beyond those listed under *Absolute Maximum Rating* may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Condition*. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

8.2 ESD Ratings

(1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

(2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

8.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

8.3 Recommended Operating Conditions (continued)

over operating free-air temperature range (unless otherwise noted)

8.4 Thermal Information

(1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC Package Thermal Metrics](http://www.ti.com/lit/SPRA953) application report.

8.5 Electrical Characteristics

VBUS=8V, VOUT=4V, T $_{\rm J}$ = -40°C to +85°C, and T $_{\rm J}$ = 25°C for typical values (unless otherwise noted)

8.6 Timing Requirements

8.7 Typical Characteristics

Typical characteristics are taken with the BMS041 for switching test and GRM188R61C226M is used as CFLY.

[BQ25960](https://www.ti.com/product/BQ25960)

8.7 Typical Characteristics (continued)

Typical characteristics are taken with the BMS041 for switching test and GRM188R61C226M is used as CFLY.

9 Detailed Description

9.1 Overview

The BQ25960 is a 98.1% peak efficiency, 8-A battery charging solution using a switched cap architecture for 1 cell Li-ion battery. This architecture allows the cable current to be half the charging current, reducing the cable power loss, and limiting temperature rise. The dual-phase architecture increases charging efficiency and reduces the input and output cap requirements. When used with a main charger such as BQ2561x or BQ2589x, the system the system enables full charging cycle from trickle charge to termination with low power loss at Constant Current (CC) and Constant Voltage (CV) mode.

The device also operates in bypass mode charging the battery directly from VBUS through QB, QCH1 and QDH1 in parallel with QCH2 and QDH2. The impedance in bypass mode is limited to 21 mΩ for 5-A charging current.

The device supports dual input power path management which manages the power flowing from two different input sources. The inputs selection is controlled by host through $1²C$ with default source #1 as the primary input and the source #2 as the secondary source.

The device integrates all the necessary protection features to ensure safe charging, including input overvoltage and overcurrent protection, output overvoltage and overcurrent protection, temperature sensing for the battery and cable, and monitoring the die temperature.

The device includes a 16-bit ADC to provide bus voltage, bus current, output voltage, battery voltage, battery current, input connector temperature, battery temperature, junction temperature, and other calculated measurements needed to manage the charging of the battery from the smart wall adapter or wireless input or power bank.

9.2 Functional Block Diagram

9.3 Feature Description

9.3.1 Charging System

BQ25960 is a single-cell high efficiency switched cap charger, used in parallel with a switching mode charger. A host must set up the protections and alarms on BQ25960 prior to enabling the BQ25960. The host must monitor the alarms generated by BQ25960 and communicate with the smart adapter to control the current delivered to the charger.

Figure 9-1. BQ25960 System Diagram

9.3.2 Battery Charging Profile

The system will have a specific battery charging profile that is unique due to the switched cap architecture. The charging will be controlled by the main charger such as the BQ2561x or BQ2589x until ystem voltage reaches minimum system regulation voltage V_{SYSMIN} . Once the battery voltage reaches V_{SYSMIN} (3.5 V), the adapter can negotiate for a higher bus voltage, enable BQ25960 charging, and regulate the current on VBUS to charge the battery. In the CC phase, the protection in BQ25960 will not regulate the battery voltage, but will provide feedback to the system to increase and decrease current as needed, as well as disable the blocking and switching FETs if the voltage is exceeded. Once the CV point is reached, the BQ25960 will provide feedback to the adapter to reduce the current, effectively tapering the current until a point where the main charger takes over again. The BQ25960 can operate as long as input current is above the BUSUCP threshold.

Figure 9-2. BQ25960 System Charging Profile

9.3.3 Device Power Up

The device is powered from the higher of VAC1 or VAC2 (with VAC1 being primary input), VBUS or VOUT (battery). The voltage must be greater than the $V_{VACUVLOZ}$, $V_{VBUSUVLOZ}$ or $V_{VOUTUVLOZ}$ threshold to be a valid supply. When VAC1 or VAC2 rises above V_{VACUVLOZ} or VBUS rises above V_{VBUSUVLOZ} or VOUT rises above $V_{VOUTUVLOZ}$, I²C interface is ready for communication and all the registers are reset to default value. The host needs to wait VBUSPRESENT_STAT and VOUTPRESENT_STAT go high before setting CHG_EN =1 and start charging.

9.3.4 Device HIZ State

The device enters HIZ mode when EN_HIZ bit is set to '1'. When device is in HIZ mode, the converter stops switching, ADC stops converting, ACDRV is turned off and REGN LDO is forced off even when the adapter is present and no fault condition is present. The device exits HIZ Mode when EN_HIZ is set to '0' by host or device POR.

The faults conditions force the converter stop switching and clear CHG_EN bit, but keep REGN on and EN_HIZ bit = 0. More details can be found in the Device Protection section.

9.3.5 Dual Input Bi-Directional Power Path Management

The device has two ACDRV pins to drive two sets of N-channel ACFET-RBFET, which select and manage the input power from two different input sources. In the POR sequence, the device detects if the ACFET-RBFET is populated based on if ACDRV pin is shorted to ground or not, and then updates the status register ACRB1_CONFIG_STAT or ACRB2_CONFIG_STAT to indicate the presence of ACFET-RBFET. If the external ACFET-RBFET is not populated in the schematic, then tie VAC to VBUS and connect ACDRV to GND. The device supports:

- 1. single input without external FET
- 2. single input with one single ACFET
- 3. dual input with one set of ACFET-RBFET
- 4. dual input with two sets of ACFET-RBFET

The power-up sequences for different applications are described in detail below.

FYAS

Instruments

9.3.5.1 ACDRV Turn-On Condition

The ACDRV controls input power MUX for both BQ25960 and main charger. In order to turn the ACDRV, all of the following conditions must be valid:

- 1. The corresponding AC-RB FET is populated: VAC is not short to VBUS and ACDRV is not short to ground
- 2. VAC is above V_{VACpresent} threshold
- 3. VAC is below V_{VACOVP} threshold
- 4. DIS_ACDRV_BOTH is not set to '1'
- 5. EN_HIZ is not set to '1'
- 6. VBUS is below $V_{VBUSpresent}$ threshold

9.3.5.2 Single Input from VAC to VBUS without ACFET-RBFET

In this scenario, VAC1 and VAC2 are both shorted to VBUS, ACDRV1 and ACDRV2 are pulled down to ground. The table below summarizes the VAC1/VAC2, ACDRV1/ACDRV2 connection, register control, and status functions.

Table 9-1. Single Input without External FET Summary

Figure 9-3. Single input without ACFET-RBFET

9.3.5.3 Single Input with ACFET1

In this scenario, ACFET1 without RBFET1 is populated, but ACFET2-RBFET2 is not. VAC2 is short to VBUS and ACDRV2 is pulled down to ground. The table below summarizes the VAC1/ VAC2, ACDRV1/ACDRV2 connection, register control, and status functions. Use VAC1 for single input configuration.

Table 9-2. Single Input with Single ACFET1

Table 9-2. Single Input with Single ACFET1 (continued)

Figure 9-4. Single Input with ACFET1

9.3.5.4 Dual Input with ACFET1-RBFET1

In this scenario, ACFET1-RBFET1 is populated, but ACFET2-RBFET2 is not. VAC2 is short to VBUS and ACDRV2 is pulled down to ground. The table below summarizes the connection, register control and status functions. Use VAC1 for adapter input and VBUS for wireless input.

Table 9-3. Dual Input with ACFET1-RBFET1

Figure 9-5. Dual Input with ACFET-RBFET1

9.3.5.5 Dual Input with ACFET1-RBFET1 and ACFET2-RBFET2

In this scenario, both ACFET1-RBFET1 and ACFET2-RBFET2 are populated and the device supports dual input. The table below summarizes the connection, register control and status functions. Connect input with high OVP threshold to VAC1.

9.3.5.6 OTG and Reverse TX Mode Operation

When the main charger is in OTG or reverse TX Mode, the input power MUX (ACFET-RBFET) also controls which port is desired for OTG output.

To enter OTG or reverse TX Mode, the host should follow the steps below:

- 1. Host writes EN_OTG =1
- 2. BQ25960 sets DIS_ACDRV_BOTH =1
- 3. Host writes DIS_ACDRV_BOTH=0, and then writes ACDRV1_STAT=1 or ACDRV2_STAT=1 depending on which port is desired for OTG or reverse TX output
- 4. Host enables OTG Mode on main charger
- 5. If VBUSOVP or VACOVP fault occurs, ACDRV will be disabled but EN_OTG is still '1'. Host needs to write ACDRV1_STAT high or ACDRV2_STAT high when the fault is cleared. Set VAC1OVP and VAC2OVP to the same threshold in the OTG Mode
- 6. EN_OTG is cleared when watchdog timer expires

To exit OTG or Reverse TX Mode, the host should follow the steps below:

- 1. Turn off main OTG or reverse TX source
- 2. Turn on VBUS pulldown resistor (R_{VBUS PD}) by setting BUS_PD_EN=1 or VAC pulldown resistor R_{VAC PD} by setting VAC1_PD_EN=1 or VAC2_PD_EN=1, depending on which port is to be discharged
- 3. Wait for VBUS and VAC to be discharged
- 4. Turn off ACDRV by setting ACDRV1_STAT=0 or ACDRV2_STAT=0
- 5. Exit OTG Mode by setting EN_OTG=0

9.3.6 Bypass Mode Operation

When host determines the adapter support bypass mode charging, the device can enable Bypass mode by setting EN BYPASS=1. Blocking FET (Q_B) and four high side switching FET (QCH1 and QDH1/ QCH2 and QDH2) are turned on to charge from adapter to battery. During Bypass Mode, when fault occurs, CHG_EN is cleared but EN_BYPASS stays '1'.

Figure 9-7. BQ25960 Bypass Mode

To change from Bypass Mode to Switched Cap Mode or from Switched Cap to Bypass Mode, the host would first set CHG EN=0 to stop the converter and then set EN BYPASS to desired value. The host sets desired protection threshold based on the selected operation modes and then host enables charge by setting CHG_EN=1.

9.3.7 Charging Start-Up

The host can start Switched Cap or Bypass Mode charging follow the steps below:

- 1. Both VBUS and VOUT need to be present. Host can check the status through VBUSPRESENT_STAT (REG15[2]) and VOUTPRSENT_STAT (REG15[5]). Both of them need to be '1'.
- 2. Host sets all the protections to the desired thresholds. Refer to the [Device Modes and Protection Status](#page-23-0) section for proper setting.
- 3. Host sets either Switched Cap Mode or Bypass Mode through EN_BYPASS bit (REG0F[3]) based on adapter type.
- 4. Host sets the desired switching frequency in Switched Cap Mode through FSW_SET [2:0] bits (REG10[7:5]).
- 5. Host sets BUS under current protection (BUSUCP) to 250 mA though BUSUCP bit (REG05[6])=1
- 6. Host sets charger configuration bits: CHG_CONFIG_1 (REG05[3])=1.
- 7. Host can enable charge by setting CHG_EN=1.
- 8. Once charge has been enabled, the CONV_ACTIVE_STAT bit is set to '1' to indicate either switched cap or bypass is active, and current starts to flow to the battery.
- 9. When watchdog timer expires, CHG EN is reset to '0' and charging stops. Host needs to read or write any register bit before watchdog expires, or disable watchdog timer (set REG10[2]=1) to prevent watchdog timer from expiring.

9.3.8 Adapter Removal

If adapter is removed during soft start timer, CHG_EN will be cleared after soft-start timer expires. The user can program the soft-start timer in SS_TIMEOUT register. If adapter is removed after soft-start timer expires, converter stops switching and CHG_EN is cleared after the deglitch time programmed in

IBUSUCP_FALL_DG_SEL register. The device prevents boost back when the adapter is removed during and after the soft-start timer. To accelerate VBUS or VAC discharge after adapter removal, the user to turn on the VBUS pulldown resistor (R_{VBUS} _{PD}) and VAC pulldown current resistor (R_{VAC} _{PD}) by setting BUS_PD_EN or VAC1_PD_EN or VAC2_PD_EN to '1'.

9.3.9 Integrated 16-Bit ADC for Monitoring and Smart Adapter Feedback

The integrated 16-bit ADC of the device allows the user to get critical system information for optimizing the behavior of the charger control. The control of the ADC is done through the ADC control register. The ADC_EN bit provides the ability to enable and disable the ADC to conserve power. The ADC_RATE bit allows continuous conversion or one-shot behavior. The ADC_AVG bit enables or disables (default) averaging. ADC_AVG_INIT starts average using the existing (default) or using a new ADC value.

To enable the ADC, the ADC_EN bit must be set to '1'. The ADC is allowed to operate if the V_{VAC}>V_{VACPRESENT}, V_{VBUS}>V_{VBUSPRESENT} or V_{VOUT}>V_{VOUTPRESENT} is valid. If ADC_EN is set to '1' before VAC, VBUS or VOUT reach their respective PRESENT threshold, then the ADC conversion will be postponed until one of the power supplies reaches the threshold.

The ADC SAMPLE bits control the sample speed of the ADC, with conversion times of t_{ADC} conv. The integrated ADC has two rate conversion options: a 1-shot mode and a continuous conversion mode set by the ADC_RATE bit. By default, all ADC parameters will be converted in 1-shot or continuous conversion mode unless disabled in the ADC CONTROL 1 and ADC_CONTROL 2 register. If an ADC parameter is disabled by setting the corresponding bit in the ADC CONTROL 1 and ADC CONTROL 2 register, then the value in that register will be from the last valid ADC conversion or the default POR value (all zeros if no conversions have taken place). If an ADC parameter is disabled in the middle of an ADC measurement cycle, the device will finish the conversion of that parameter, but will not convert the parameter starting the next conversion cycle. Even though no conversion takes place when all ADC measurement parameters are disabled, the ADC circuitry is active and ready to begin conversion as soon as one of the bits in the ADC CONTROL 1 and ADC_CONTROL 2 register is set to '0'.

The ADC_DONE_* bits signal when a conversion is complete in 1-shot mode only. During continuous conversion mode, the ADC DONE * bits have no meaning and will be '0'.

ADC conversion operates independently of the faults present in the device. ADC conversion will continue even after a fault has occurred (such as one that causes the power stage to be disabled), and the host must set ADC_EN = '0' to disable the ADC. ADC readings are only valid for DC states and not for transients. When host writes ADC_EN=0, the ADC stops immediately. If the host wants to exit ADC more gracefully, it is possible to do either of the following:

1. Write ADC_RATE to one-shot, and the ADC will stop at the end of a complete cycle of conversions, or

2. Write all the DIS bits low, and the ADC will stop at the end of the current measurement.

When external sense resistor (RSNS) is placed and IBATADC is used, it is recommended to use 375-kHz switching frequency.

9.3.10 Device Modes and Protection Status

Table 9-5 shows the features and modes of the device depending on the conditions of the device.

Table 9-5. Device Modes and Protection Status

Table 9-5. Device Modes and Protection Status (continued)

Tripping any of these protections causes Q_B to be off and converter stops switching. Masking the fault or alarm does NOT disable the protection, but only keeps an INT from being triggered by the event. Disabling the fault or alarm protection other than BUSUCP holds that STAT and FLAG bits in reset, and also prevents an interrupt from occurring. Disable BUSUCP protection still sets STAT and FLAT bits and sends interrupt to alert host but keeps converter running when triggered.

When any OVP, OCP, RCP or overtemperature fault event is triggered, the CHG_EN bit is set to '0' to disable charging, and the charging start-up sequence must be followed to begin charging again.

9.3.10.1 Input Overvoltage, Overcurrent, Undercurrent, Reverse-Current and Short-Circuit Protection

Input overvoltage protection with external single or back-to-back N-channel FET(s): The device integrates the functionality of an input overvoltage protector. With external single or back-to-back N-channel FET(s), the device blocks high input voltage exceeding VACOVP threshold (VAC1OVP or VAC2OVP). This eliminates the need for a separate OVP device to protect the overall system. The integrated VACOVP feature has a response time of t_{VACOVP} (the actual time to turn off external FET(s) will be longer and depends upon the FET(s) gate capacitance). The VAC1OVP and VAC2OVP setting is adjustable in the VAC control register. The part allows the user to have different VAC1OVP and VAC2OVP settings. Always put the high VACOVP threshold input to VAC1.

When VAC1OVP or VAC2OVP is tripped, corresponding ACDRV is turned off and VAC1OVP STAT or VAC2OVP_STAT and VAC1OVP_FLAG or VAC2OVP_FLAG is set to '1', and INT is asserted low to alert the host (unless masked by VAC1OVP_MASK or VAC2OVP_MASK). When VAC2OVP is triggered, the device sends multiple interrupts when the fault persists. Use VAC1 as input unless both VAC1 and VAC2 are needed.

Input overvoltage protection (BUSOVP): The BUSOVP threshold is adjustable in the BUSOVP register. When BUSOVP is tripped, switched cap or bypass mode is disabled and CHG_EN is set to '0'. BUSOVP_STAT and BUSOVP_FLAG is set to '1', and INT is asserted low to alert the host (unless masked by BUSOVP_MASK). The start-up sequence must be followed to resume charging.

Input overcurrent protection (BUSOCP): Input overcurrent protection monitors the current flow into VBUS. The overcurrent protection threshold is adjustable in the BUSOCP register. When BUSOCP is tripped, Switched Cap or Bypass Mode is disabled and CHG_EN is set to '0'. BUSOCP_STAT and BUSOCP_FLAG is set to '1', and INT is asserted low to alert the host (unless masked by BUSOCP MASK). The start-up sequence must be followed to resume charging.

Input undercurrent protection (**BUSUCP)**: BUS undercurrent protection (UCP) is implemented to detect adapter unplug. Set BUSUCP =1 (REG05[6]) before enable charge. When BUSUCP is enabled (BUSUCP_DIS=0), if the current is below BUSUCP after soft start timer (programmable in SS_TIMEOUT[2:0]) expires, Switched Cap or Bypass Mode is disabled and CHG_EN is set to '0'. BUSUCP_STAT and BUSUCP_FLAG is set to '1', and INT is asserted low to alert the host (unless masked by BUSUCP_MASK). The start-up sequence must be followed to resume charging. The deglitch time for BUSUCP is programmable in IBUSUCP_FALL_DG_SET[1:0] register. Please note that BUSUCP deglitch time needs to be set shorter than soft start timer in order for BUSUCP to be effective.

When BUSUCP is disabled (BUSUCP DIS=1), if the current is below BUSUCP after soft-start timer expires, CHG_EN is not set to '0', BUSUCP_STAT and BUSUCP_FLAG is set to '1', and INT is asserted low to alert the host (unless masked by BUSUCP_MASK). The host can determine if charge needs to be stopped in this case.

Input reverse-current protection (**BUSRCP**): The device monitors the current flow from VBUS to VBAT to ensure there is no reverse current (current flow from VBAT to VBUS). In an event that a reverse current flow is detected when BUSRCP_DIS is set to '0', the Switched Cap or Bypass is disabled and CHG_EN is set to '0'. The start-up sequence must be followed to resume charging. To disable BUSRCP, set REG05[1:0] to '00' and then set BUSRCP_DIS=1.

RCP is always active when converter is switching and BUSRCP DIS is set to '0'. When RCP is tripped, BUSRCP_STAT and BUSRCP_FLAG is set to '1', and $\overline{\text{INT}}$ is asserted low to alert the host (unless masked by BUSRCP_MASK).

Input overvoltage and overcurrent protection alarm (**BUSOVP_ALM and BUSOCP_ALM):** In addition to input overvoltage and overcurrent, the device also integrates alarm function BUSOVP_ALM and BUSOCP_ALM. When alarm is triggered, the corresponding STAT and FLAG bit is set to '1' and INT is asserted low to alert the host (unless it is masked by the MASK bit). However, CHG_EN is not cleared and host can reduce input voltage or input current to prevent VBUS reaching VBUSOVP threshold or IBUS reaching IBUSOCP threshold.

VBUS ERRHI: the device monitors VBUS to VOUT voltage ratio. If VBUS/VOUT is greater than VBUS ERRHI RISING threshold, the converter does not switch but CHG_EN is kept at '1'. The converter automatically starts switching when the VBUS/VOUT drops below $V_{BUSERRH}$ EALLING threshold.

9.3.10.2 Battery Overvoltage and Overcurrent Protection

BATOVP and BATOVP_ALM: The device integrates both overcurrent and overvoltage protection for the battery. The device monitors the battery voltage on BATP and BATN_SRP. In order to reduce the possibility of battery terminal shorts during manufacturing, 100-Ω series resistors on BATP is required. If external sense resistor is not used, place 100-Ω series resistors on BATN as well. The device is intended to be operated within the window formed by the BATOVP and BATOVP_ALM. When the BATOVP_ALM is reached, an interrupt is sent to the host to reduce the charge current and thereby not reaching the BATOVP threshold. If BATOVP is reached, the switched cap or bypass is disabled and CHG_EN is set to '0', and the start-up sequence must be followed to resume charging. At the same time, BATOVP_STAT and BATOVP_FLAG are set to '1', and INT is asserted low to alert the host (unless masked by BATOVP_MASK). BATOVP and BATOVP_ALM is disabled when BATOVP_DIS and BATOVP_ALM_DIS is set to '1'.

BATOCP and BATOCP_ALM: The device monitors current through the battery by monitoring the voltage across the external series battery sense resistor. The differential voltage of this sense resistor is measured on BATN_SRP and SRN_SYNCIN. The device is intended to be operated within the window formed by the BATOCP and BATOCP ALM. When the BATOCP ALM is reached, an interrupt is sent to the host to reduce the charge current from reaching the BATOCP threshold. If BATOCP is reached, the Switched Cap or Bypass is disabled after a deglitch time of t_{BATOCP} and CHG_EN is set to '0', and the start-up sequence must be followed to resume charging. At the same time, BATOCP_STAT and BATOCP_FLAG are set to '1', and INT is asserted

low to alert the host (unless masked by BATOCP_MASK). BATOCP and BATOCP_ALM is disabled when BATOCP_DIS and BATOCP_ALM_DIS is set to '1'.

VOUTOVP: The device also monitors output voltage between VOUT and ground in case of battery removal to protect the system. If VOUTOVP is reached and VOUTOVP_DIS=0, the Switched Cap or Bypass is disabled and CHG_EN is set to '0', and the start-up sequence must be followed to resume charging. At the same time, VOUTOVP_STAT and VOUTOVP_FLAG is set to '1', and INT is asserted low to alert the host (unless masked by VOUTOVP_MASK). If VOUTOVP_DIS =1, the protection is disabled.

9.3.10.3 IC Internal Thermal Shutdown, TSBUS, and TSBAT Temperature Monitoring

The device has three temperature sensing mechanisms to protect the device and system during charging:

- 1. TSBUS for monitoring the cable connector temperature
- 2. TSBAT for monitoring the battery temperature
- 3. TDIE for monitoring the internal junction temperature of the device

The TSBUS and TSBAT both rely on a resistor divider that has an external pullup voltage to REGN. Place a negative coefficient thermistor (NTC) in parallel to the low-side resistor. A fault on the TSBUS and TSBAT pin is triggered on the falling edge of the voltage threshold, signifying a "hot" temperature. The threshold is adjusted using the TSBUS_FLT and TSBAT_FLT registers.

The typical TS resistor network on TSBAT SYNCOUT is illustrated in Figure 9-8. The resistor network on TSBUS is the same.

Figure 9-8. TSBAT_SYNCOUT Resistor Network

The RLO and RHI resistors should be chosen depending on the NTC used. If a 10-kΩ NTC is used, use 10-kΩ resistors for RLO and RHI. If a 100-kΩ NTC is used, use 100-kΩ resistors for RLO and RHI. The ratio of VTS/ REGN can be from 0% to 50%, and the voltage at the TS pin is determined by the following equation.

$$
TSBUS\ or\ TSBAT\ (V) = \frac{\frac{1}{(\frac{1}{RNTC} + \frac{1}{RLO})}}{RHI + \frac{1}{(\frac{1}{RNTC} + \frac{1}{RLO})}} \times VREGN
$$
\n
$$
(1)
$$

The percentage of the TS pin voltage is determined by the following equation.

$$
TSBUS or TSBAT (%) = \frac{\frac{1}{(\frac{1}{RNTC} + \frac{1}{RLO})}}{RHI + \frac{1}{(\frac{1}{RNTC} + \frac{1}{RLO})}}
$$
\n(2)

Additionally, the device measures internal junction temperature, with adjustable threshold TDIE_FLT in TDIE_FLT register.

If the TSBUS FLT, TSBAT FLT, and TDIE FLT thresholds are reached, the Switched Cap or Bypass Mode is disabled and CHG_EN is set to '0', and the start-up sequence must be followed to resume charging. The corresponding STAT and FLAG bit is set to '1' unless it is masked by the MASK bit. If TSBUS, TSBAT, or TDIE protections are not used, the functions can be disabled in the register by setting the TSBUS_FLT_DIS, TSBAT_FLT_DIS, or TDIE_FLT_DIS bit to '1'.

TSBUS_TSBAT_ALM_STAT and FLAG is set to '1' unless it is masked by corresponding mask bit when one of the following conditions is met: 1) TSBUS is within 5% of TSBUS_FLT threshold or 2) TSBAT is within of TSBAT_FLT. If the TSBUS_FLT or TSBAT_FLT is disabled, it will not trigger a TSBUS_TSBAT_ALM interrupt. Using the TDIE_ALM register, an alarm can be set to notify the host when the device die temperature exceeds a threshold. The TDIE_ALM_STAT and TDIE_ALM_FLAG bit is set to '1' unless it is masked by TDIE_ALM_MASK bit. The device will not automatically stop switching when reaching the alarm threshold and the host may decide on the steps to take to lower the temperature, such as reducing the charge current.

9.3.11 INT Pin, STAT, FLAG, and MASK Registers

The $\overline{\text{INT}}$ pin is an open drain pin that needs to be pulled up to a voltage with a pullup resistor. $\overline{\text{INT}}$ is normally high and will assert low for t_{INT} when the device needs to alert the host of a fault or status change.

The fields in the STAT registers show the current status of the device, and are updated as the status changes. The fields in the FLAG registers indicate that the event has occurred, and the field is cleared when read. If the event persists after the FLAG register has been read and cleared, another $\overline{\text{INT}}$ signal is not sent to prevent host keep receiving interrupts. The fields in the MASK registers allow the user to disable the interrupt on the $\overline{\text{INT}}$ pin, but the STAT and FLAG registers are still updated even though $\overline{\text{INT}}$ is not pulled low.

9.3.12 Dual Charger Operation Using Primary and Secondary Modes

For higher power systems, it is possible to use two devices in dual charger configuration. This allows each device to operate at lower charging current with higher efficiency compared with single device operating at the same total charging current. The CDRVL ADDRMS pin is used to configure the functionality of the device as Standalone, Primary or Secondary during POR. Refer to [Section 9.3.13](#page-28-0) for proper setting. When configured as a primary, the TSBAT_SYNCOUT pin functions as SYNCOUT, and the SRN_SYNCIN pin functions as SRN. When configured as a Secondary, the TSBAT_SYNCOUT pin functions as TSBAT, and the SRN_SYNCIN pin functions as SYNCIN. ACDRV1 and ACDRV2 are controlled by the primary, and ACDRV1 and ACDRV2 on the secondary should be grounded. Pull the SYNCIN/SYNCOUT pins to REGN on the primary BQ25960 through a 1-kΩ resistor. The maximum switching frequency in primary and secondary mode is 500 kHz.

The dual charger can operate in Primary and Secondary Mode in Bypass Mode as well. In both Bypass and Switched Cap Mode, the current distribution between the two devices depends on loop impedance and the chargers do not balance it. In order balance the current, the board layout needs to be as symmetrical as possible.

Figure 9-9. Parallel Operation of BQ25960

9.3.13 CDRVH and CDRVL_ADDRMS Functions

The device requires a cap between the CDRVH and CDRVL_ADDRMS pin to operate correctly. The CDRVL_ADDRMS pin also allows setting the default I2C address and device operation mode. Pull to GND with a resistor for the desired setting shown in Table 9-6. The surface mount resistor with ±1% tolerance is recommended. After POR, the host can read back the device's configuration from MS register (REG12[1:0]).

Table 9-6. I2C Address and Mode Selection

9.4 Programming

The device uses an I²C compatible interface to program and read many parameters. I²C is a 2-wire serial interface developed by NXP (formerly Philips Semiconductor, see I²C BUS Specification, Version 5, October 2012). The BUS consists of a data line (SDA) and a clock line (SCL) with pullup structures. When the BUS is idle, both SDA and SCL lines are pulled high. All the I²C compatible devices connect to the I²C BUS through open drain I/O terminals, SDA and SCL. A master device, usually a microcontroller or digital signal processor, controls the BUS. The master is responsible for generating the SCL signal and device addresses. The master

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also generates specific conditions that indicate the START and STOP of data transfer. A slave device receives and/or transmits data on the BUS under control of the master device.

The device works as a slave and supports the following data transfer modes, as defined in the I²C BUS™ Specification: standard mode (100 kbps) and fast mode (400 kbps). The interface adds flexibility to the battery management solution, enabling most functions to be programmed to new values depending on the instantaneous application requirements. The I²C circuitry is powered from the battery in active battery mode. The battery voltage must stay above VBATUVLO when no VIN is present to maintain proper operation.

The data transfer protocol for standard and fast modes is exactly the same; therefore, they are referred to as the F/S-mode in this document. The device only supports 7-bit addressing. The device 7-bit address is determined by the ADDR pin on the device.

9.4.1 F/S Mode Protocol

The master initiates data transfer by generating a start condition. The start condition is when a high-to-low transition occurs on the SDA line while SCL is high, as shown in the figure below. All I2C-compatible devices should recognize a start condition.

Figure 9-10. START and STOP Condition

The master then generates the SCL pulses, and transmits the 8-bit address and the read/write direction bit R/W on the SDA line. During all transmissions, the master ensures that data is valid. A valid data condition requires the SDA line to be stable during the entire high period of the clock pulse (see Figure 9-11). All devices recognize the address sent by the master and compare it to their internal fixed addresses. Only the slave device with a matching address generates and acknowledge (see [Figure 9-12\)](#page-30-0) by pulling the SDA line low during the entire high period of the ninth SCL cycle. Upon detecting this acknowledge, the master knows that communication link with a slave has been established.

Figure 9-11. Bit Transfer on the Serial Interface

Figure 9-12. Acknowledge on the I2C BUS

The master generates further SCL cycles to either transmit data to the slave (R/W bit 0) or receive data from the slave (R/W bit 1). In either case, the receiver needs to acknowledge the data sent by the transmitter. An acknowledge signal can either be generated by the master or by the slave, depending on which on is the receiver. The 9-bit valid data sequences consisting of 8-bit data and 1-bit acknowledge can continue as long as necessary. To signal the end of the data transfer, the master generates a stop condition by pulling the SDA line from low to high while the SCL line is high (see Figure 9-13). This releases the BUS and stops the communication link with the addressed slave. All I2C compatible devices must recognize the stop condition. Upon the receipt of a stop condition, all devices know that the BUS is released, and wait for a start condition followed by a matching address. If a transaction is terminated prematurely, the master needs to send a STOP condition to prevent the slave $1²C$ logic from remaining in an incorrect state. Attempting to read data from register addresses not listed in this section will result in 0xFFh being read out.

Figure 9-13. BUS Protocol

9.5 Register Maps

9.5.1 I2C Registers

Table 9-7 lists the I²C registers. All register offset addresses not listed in Table 9-7 should be considered as reserved locations and the register contents should not be modified. All register bits marked 'RESERVED' in Field column should not be modified.

Complex bit access types are encoded to fit into small table cells. Table 9-8 shows the codes that are used for access types in this section.

Table 9-8. I2C Access Type Codes

9.5.1.1 REG00_BATOVP Register (Offset = 0h) [reset = 5Ah]

REG00_BATOVP is shown in Table 9-9

Return to the [Summary Table.](#page-31-0)

BATOVP

Table 9-9. REG00_BATOVP Register Field Descriptions

9.5.1.2 REG01_BATOVP_ALM Register (Offset = 1h) [reset = 46h]

REG01_BATOVP_ALM is shown in [Table 9-10.](#page-33-0)

Return to the [Summary Table.](#page-31-0)

BATOVP_ALM

Table 9-10. REG01_BATOVP_ALM Register Field Descriptions

9.5.1.3 REG02_BATOCP Register (Offset = 2h) [reset = 47h]

REG02_BATOCP is shown in Table 9-11.

Return to the [Summary Table.](#page-31-0)

BATOCP

Table 9-11. REG02_BATOCP Register Field Descriptions

9.5.1.4 REG03_BATOCP_ALM Register (Offset = 3h) [reset = 46h]

REG03_BATOCP_ALM is shown in Table 9-12.

Return to the [Summary Table.](#page-31-0)

BATOCP_ALM

Table 9-12. REG03_BATOCP_ALM Register Field Descriptions

FXAS

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Table 9-12. REG03_BATOCP_ALM Register Field Descriptions (continued)

9.5.1.5 REG04_BATUCP_ALM (Offset = 4h) [reset = 28h]

REG04 BATUCP ALM is shown in Table 9-13.

Return to the [Summary Table.](#page-31-0)

BATUCP_ALM

Table 9-13. REG04_BATUCP_ALM Register Field Descriptions

9.5.1.6 REG05_CHARGER_CONTROL 1 Register (Offset = 5h) [reset = 2h]

REG05_CHARGER_CONTRL 1 is shown in Table 9-14.

Return to the [Summary Table.](#page-31-0)

CHARGER_CONTROL 1

Table 9-14. REG05_CHARGER_CONTROL 1 Register Field Descriptions

Table 9-14. REG05_CHARGER_CONTROL 1 Register Field Descriptions (continued)

9.5.1.7 REG06_BUSOVP Register (Offset = 6h) [reset = 26h]

REG06_BUSOVP is shown in Table 9-15.

Return to the [Summary Table.](#page-31-0)

BUSOVP

Table 9-15. REG06_BUSOVP Register Field Descriptions

9.5.1.8 REG07_BUSOVP_ALM Register (Offset = 7h) [reset = 22h]

REG07_BUSOVP_ALM is shown in Table 9-16.

Return to the [Summary Table.](#page-31-0)

BUSOVP_ALM

Table 9-16. REG07_BUSOVP_ALM Register Field Descriptions

9.5.1.9 REG08_BUSOCP Register (Offset = 8h) [reset = Bh]

REG08_BUSOCP is shown in [Table 9-17](#page-37-0).

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BUSOCP

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Table 9-17. REG08_BUSOCP Register Field Descriptions

9.5.1.10 REG09_BUSOCP_ALM Register (Offset = 9h) [reset = Ch]

REG09_BUSOCP_ALM is shown in Table 9-18.

Return to the [Summary Table.](#page-31-0)

BUSOCP_ALM

Table 9-18. REG09_BUSOCP_ALM Register Field Descriptions

9.5.1.11 REG0A_TEMP_CONTROL Register (Offset = Ah) [reset = 60h]

REG0A_TEMP_CONTROL is shown in Table 9-19.

Return to the [Summary Table.](#page-31-0)

TEMP_CONTROL

Table 9-19. REG0A_TEMP_CONTROL Register Field Descriptions

Table 9-19. REG0A_TEMP_CONTROL Register Field Descriptions (continued)

9.5.1.12 REG0B_TDIE_ALM Register (Offset = Bh) [reset = C8h]

REG0B_TDIE_ALM is shown in Table 9-20.

Return to the [Summary Table.](#page-31-0)

TDIE_ALM

Table 9-20. REG0B_TDIE_ALM Register Field Descriptions

9.5.1.13 REG0C_TSBUS_FLT Register (Offset = Ch) [reset = 15h]

REG0C_TSBUS_FLT is shown in [Table 9-21](#page-39-0).

Return to the [Summary Table.](#page-31-0)

TSBUS_FLT

Table 9-21. REG0C_TSBUS_FLT Register Field Descriptions

9.5.1.14 REG0D_TSBAT_FLT Register (Offset = Dh) [reset = 15h]

REG0D_TSBAT_FLG is shown in Table 9-22.

Return to the [Summary Table.](#page-31-0)

TSBAT_FLG

Table 9-22. REG0D_TSBAT_FLT Register Field Descriptions

9.5.1.15 REG0E_VAC_CONTROL Register (Offset = Eh) [reset = 0h]

REG0E_VAC_CONTROL is shown in Table 9-23.

Return to the [Summary Table.](#page-31-0)

VAC_CONTROL

Table 9-23. REG0E_VAC_CONTROL Register Field Descriptions

Table 9-23. REG0E_VAC_CONTROL Register Field Descriptions (continued)

9.5.1.16 REG0F_CHARGER_CONTROL 2 Register (Offset = Fh) [reset = 0h]

REG0F_CHARGER_CONTROL 2 is shown in Table 9-24.

Return to the [Summary Table.](#page-31-0)

CHARGER CONTROL 2

Table 9-24. REG0F_CHARGER_CONTROL 2 Register Field Descriptions

Table 9-24. REG0F_CHARGER_CONTROL 2 Register Field Descriptions (continued)

9.5.1.17 REG10_CHARGER_CONTROL 3 Register (Offset = 10h) [reset = 83h]

REG10 CHARGER CONTROL 3 is shown in Table 9-25.

Return to the [Summary Table.](#page-31-0)

CHARGER CONTROL 3

Table 9-25. REG10_CHARGER_CONTROL 3 Register Field Descriptions

9.5.1.18 REG11_CHARGER_CONTROL 4 Register (Offset = 11h) [reset = 71h]

REG11_CHARGER_CONTROL 4 is shown in [Table 9-26.](#page-42-0)

Return to the [Summary Table.](#page-31-0)

CHARGER CONTROL 4

Table 9-26. REG11_CHARGER_CONTROL 4 Register Field Descriptions

9.5.1.19 REG12_CHARGER_CONTROL 5 Register (Offset = 12h) [reset = 60h]

REG12_CHARGER_CONTROL 5 is shown in Table 9-27.

Return to the [Summary Table.](#page-31-0)

CHARGER CONTROL 5

Table 9-27. REG12_CHARGER_CONTROL 5 Register Field Descriptions

Table 9-27. REG12_CHARGER_CONTROL 5 Register Field Descriptions (continued)

9.5.1.20 REG13_STAT 1 Register (Offset = 13h) [reset = 0h]

REG13_STAT 1 is shown in Table 9-28.

Return to the [Summary Table.](#page-31-0)

STAT 1

Table 9-28. REG13_STAT 1 Register Field Descriptions

Table 9-28. REG13_STAT 1 Register Field Descriptions (continued)

9.5.1.21 REG14_STAT 2 Register (Offset = 14h) [reset = 0h]

REG14_STAT 2 is shown in Table 9-29.

Return to the [Summary Table.](#page-31-0)

STAT 2

Table 9-29. REG14_STAT 2 Register Field Descriptions

9.5.1.22 REG15_STAT 3 Register (Offset = 15h) [reset = 0h]

REG15_STAT 3 is shown in Table 9-30.

Return to the [Summary Table.](#page-31-0)

STAT 3

Table 9-30. REG15_STAT 3 Register Field Descriptions

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Table 9-30. REG15_STAT 3 Register Field Descriptions (continued)

9.5.1.23 REG16_STAT 4 Register (Offset = 16h) [reset = 0h]

REG16_STAT 4 is shown in Table 9-31.

Return to the [Summary Table.](#page-31-0)

STAT 4

Table 9-31. REG16_STAT 4 Register Field Descriptions

Return to the [Summary Table.](#page-31-0)

9.5.1.24 REG17_STAT 5 Register (Offset = 17h) [reset = 0h]

REG17_STAT 5 is shown in Table 9-32.

STAT 5

Table 9-32. REG17_STAT 5 Register Field Descriptions

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Table 9-32. REG17_STAT 5 Register Field Descriptions (continued)

9.5.1.25 REG18_FLAG 1 Register (Offset = 18h) [reset = 0h]

REG18_FLAG 1 is shown in Table 9-33.

Return to the [Summary Table.](#page-31-0)

FLAG 1

Table 9-33. REG18_FLAG 1 Register Field Descriptions

9.5.1.26 REG19_FLAG 2 Register (Offset = 19h) [reset = 0h]

REG19_FLAG 2 is shown in [Table 9-34](#page-48-0).

Return to the [Summary Table.](#page-31-0)

FLAG 2

Table 9-34. REG19_FLAG 2 Register Field Descriptions

9.5.1.27 REG1A_FLAG 3 Register (Offset = 1Ah) [reset = 0h]

REG1A_FLAG 3 is shown in Table 9-35.

Return to the [Summary Table.](#page-31-0)

FLAG 3

Table 9-35. REG1A_FLAG 3 Register Field Descriptions

Table 9-35. REG1A_FLAG 3 Register Field Descriptions (continued)

9.5.1.28 REG1B_FLAG 4 Register (Offset = 1Bh) [reset = 0h]

REG1B_FLAG 4 is shown in Table 9-36.

Return to the [Summary Table.](#page-31-0)

FLAG 4

Table 9-36. REG1B_FLAG 4 Register Field Descriptions

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Table 9-36. REG1B_FLAG 4 Register Field Descriptions (continued)

9.5.1.29 REG1C_FLAG 5 Register (Offset = 1Ch) [reset = 0h]

REG1C_FLAG 5 is shown in Table 9-37.

Return to the [Summary Table.](#page-31-0)

FLAG 5

Table 9-37. REG1C_FLAG 5 Register Field Descriptions

9.5.1.30 REG1D_MASK 1 Register (Offset = 1Dh) [reset = 0h]

REG1D_MASK 1 is shown in Table 9-38.

Return to the [Summary Table.](#page-31-0)

MASK 1

Table 9-38. REG1D_MASK 1 Register Field Descriptions

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9.5.1.31 REG1E_MASK 2 Register (Offset = 1Eh) [reset = 0h]

REG1E_MASK 2 is shown in Table 9-39.

Return to the [Summary Table.](#page-31-0)

MASK 2

Table 9-39. REG1E_MASK 2 Register Field Descriptions

9.5.1.32 REG1F_MASK 3 Register (Offset = 1Fh) [reset = 0h]

REG1F_MASK 3 is shown in Table 9-40.

Return to the [Summary Table.](#page-31-0)

MASK 3

Table 9-40. REG1F_MASK 3 Register Field Descriptions

Table 9-40. REG1F_MASK 3 Register Field Descriptions (continued)

9.5.1.33 REG20_MASK 4 Register (Offset = 20h) [reset = 0h]

REG20_MASK 4 is shown in Table 9-41.

Return to the [Summary Table.](#page-31-0)

MASK 4

Table 9-41. REG20_MASK 4 Register Field Descriptions

Table 9-41. REG20_MASK 4 Register Field Descriptions (continued)

9.5.1.34 REG21_MASK 5 Register (Offset = 21h) [reset = 0h]

REG21_MASK 5 is shown in Table 9-42.

Return to the [Summary Table.](#page-31-0)

MASK 5

Table 9-42. REG21_MASK 5 Register Field Descriptions

9.5.1.35 REG22_DEVICE_INFO Register (Offset = 22h) [reset = 0h]

REG22_DEVICE_INFO is shown in Table 9-43.

Return to the [Summary Table.](#page-31-0)

DEVICE INFO

Table 9-43. REG22_DEVICE_INFO Register Field Descriptions

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9.5.1.36 REG23_ADC_CONTROL 1 Register (Offset = 23h) [reset = 0h]

REG23_ADC_CONTROL 1 is shown in Table 9-44.

Return to the [Summary Table.](#page-31-0)

ADC_CONTROL 1

Table 9-44. REG23_ADC_CONTROL 1 Register Field Descriptions

9.5.1.37 REG24_ADC_CONTROL 2 Register (Offset = 24h) [reset = 0h]

REG24_ADC_CONTROL 2 is shown in Table 9-45.

Return to the [Summary Table.](#page-31-0)

ADC_CONTROL 2

Table 9-45. REG24_ADC_CONTROL 2 Register Field Descriptions

Table 9-45. REG24_ADC_CONTROL 2 Register Field Descriptions (continued)

9.5.1.38 REG25_IBUS_ADC Register (Offset = 25h) [reset = 0h]

REG25_IBUS_ADC is shown in Table 9-46.

Return to the [Summary Table.](#page-31-0)

IBUS_ADC

Table 9-46. REG25_IBUS_ADC Register Field Descriptions

9.5.1.39 REG27_VBUS_ADC Register (Offset = 27h) [reset = 0h]

REG27_VBUS_ADC is shown in Table 9-47.

Return to the [Summary Table.](#page-31-0)

VBUS_ADC

Table 9-47. REG27_VBUS_ADC Register Field Descriptions

9.5.1.40 REG29_VAC1_ADC Register (Offset = 29h) [reset = 0h]

REG29 VAC1 ADC is shown in Table 9-48.

Return to the [Summary Table.](#page-31-0)

VAC1_ADC

Table 9-48. REG29_VAC1_ADC Register Field Descriptions

9.5.1.41 REG2B_VAC2_ADC Register (Offset = 2Bh) [reset = 0h]

REG2B_VAC2_ADC is shown in Table 9-49.

Return to the [Summary Table.](#page-31-0)

VAC2_ADC

Table 9-49. REG2B_VAC2_ADC Register Field Descriptions

9.5.1.42 REG2D_VOUT_ADC Register (Offset = 2Dh) [reset = 0h]

REG2D_VOUT_ADC is shown in [Table 9-50.](#page-58-0)

Return to the [Summary Table.](#page-31-0)

VOUT_ADC

Table 9-50. REG2D_VOUT_ADC Register Field Descriptions

9.5.1.43 REG2F_VBAT_ADC Register (Offset = 2Fh) [reset = 0h]

REG2F_VBAT_ADC is shown in Table 9-51.

Return to the [Summary Table.](#page-31-0)

VBAT_ADC

Table 9-51. REG2F_VBAT_ADC Register Field Descriptions

9.5.1.44 REG31_IBAT_ADC Register (Offset = 31h) [reset = 0h]

REG31_IBAT_ADC is shown in Table 9-52.

Return to the [Summary Table.](#page-31-0)

IBAT_ADC

Table 9-52. REG31_IBAT_ADC Register Field Descriptions

9.5.1.45 REG33_TSBUS_ADC Register (Offset = 33h) [reset = 0h]

REG33_TSBUS_ADC is shown in Table 9-53.

Return to the [Summary Table.](#page-31-0)

TSBUS_ADC

Table 9-53. REG33_TSBUS_ADC Register Field Descriptions

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9.5.1.46 REG35_TSBAT_ADC Register (Offset = 35h) [reset = 0h]

REG35_TSBAT_ADC is shown in Table 9-54.

Return to the [Summary Table.](#page-31-0)

TSBAT_ADC

Table 9-54. REG35_TSBAT_ADC Register Field Descriptions

9.5.1.47 REG37_TDIE_ADC Register (Offset = 37h) [reset = 0h]

REG37_TDIE_ADC is shown in Table 9-55.

Return to the [Summary Table.](#page-31-0)

TDIE_ADC

Table 9-55. REG37_TDIE_ADC Register Field Descriptions

10 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

10.1 Application Information

A typical application consists of the device configured as an ${}^{12}C$ controlled parallel charger along with a standard switching charger, however, it can also be used with a linear charger or PMIC with integrated charger as well. BQ25960 can start fast charging after the main charger completes pre-charging. BQ25960 will then hand back charging to the main charger when final current tapering is desired. This point is usually where the efficiency of the main charger is acceptable for the application. The device can be used to charge Li-Ion and Li-polymer batteries used in a wide range of smartphones and other portable devices. To take advantage of the high charge current capabilities of the BQ25960, it may be necessary to charge in excess of 1C. In this case, be sure to follow the battery manufacturers recommendations closely.

10.2 Typical Application

A typical schematic is shown below with all the optional and required components shown.

10.2.1 Standalone Application Information (for use with main charger)

Figure 10-2. BQ25960 Typical Application Diagram with Single Input

10.2.1.1 Design Requirements

The design requires a smart wall adapter to provide the proper input voltage and input current to the BQ25960, following the USB_PD Programmable Power Supply (PPS) voltage steps and current steps. The design shown is capable of charging up to 8 A, although this may not be practical for some applications due to the total power loss at this operating point. Careful consideration of the thermal constraints, space constraints, and operating conditions should be done to ensure acceptable performance.

10.2.1.2 Detailed Design Procedure

The first step is to determine the number of CFLY caps to put on each phase of the design. It is important to consider the current rating of the caps, their ESR, and the capacitance rating. Be sure to consider the bias voltage derating for the caps, as the CFLY caps are biased to half of the input voltage, and this will affect their effective capacitance. An optimal system will have 3 22-µF caps per phase, for a total of 6 caps per device. It is possible to use fewer caps if the board space is limited. Using fewer caps will result in higher voltage and current ripple on the output, as well as lower efficiency.

The default switching frequency, f_{SW}, for the power stage is 500 kHz. The switching frequency can be adjusted in register 0x10h using the FSW_SET bits. It is recommended to select 500 kHz if IBATADC is not used and 375 kHz if IBATADC is used.

It is recommended to use 1-µF cap on VBUS, 10-µF cap on PMID and 22-µF cap on VOUT.

10.2.1.3 Application Curves

VAC1 and VAC2 short to VBUS, ACDRV1 and ACDRV2 short to ground

VAC1 connected to input source 1, VBUS connected to input source 2, VAC2 short to VBUS, ACDRV1 active, ACDRV2 short to ground

Figure 10-17. Power Up from VAC1 with ACFET1- RBFET1

Figure 10-19. Power Up from VAC1 with ACFET1- RBFET1 and ACFET2-RBFET2

VAC1 connected to input source, VAC2 short to VBUS, ACDRV1 active, ACDRV2 short to ground

Figure 10-16. Power Up from VAC1 with Single ACFET1

VAC1 connected to input source 1, VBUS connected to input source 2, VAC2 short to VBUS, ACDRV1 active, ACDRV2 short to ground

Figure 10-18. Plugin VAC1 When Device is Power Up From VBUS with ACFET1-RBFET1

VAC1 connected to input source 1, VAC2 connected to input source 2, ACDRV1 and ACumDRV2 active

Figure 10-20. Power Up from VAC2 with ACFET1- RBFET1 and ACFET2-RBFET2

11 Power Supply Recommendations

The BQ25960 can be powered by a standard power supply capable of meeting the input voltage and current requirements for evaluation. In the actual application, it must be used with a wall adapter that supports USB Power Delivery (PD) Programmable Power Supply (PPS) specifications.

12 Layout

12.1 Layout Guidelines

Layout is very important to maximize the electrical and thermal performance of the total system. General guidelines are provided, but the form factor, board stack-up, and proximity of other components also need to be considered to maximize the performance.

- 1. VBUS and VOUT traces should be as short and wide as possible to accommodate for high current.
- 2. Copper trace of VBUS and VOUT should run at least 150 mil (3.81 mm) straight (perpendicular to WCSP ball array) before making turns.
- 3. CFLY caps should be placed as close as possible to the device and CFLY trace should be as wide as possible until close to the IC.
- 4. CLFY pours should be as symmetrical between CFH pads and CFL pads as possible.
- 5. Place low ESR bypass capacitors to ground for VBUS, PMID, and VOUT. The capacitor should be placed as close to the device pins as possible.
- 6. The CFLY pads should be as small as possible, and the CFLY caps placed as close as possible to the device, as these are switching pins and this will help reduce EMI.
- 7. Do not route so the power planes are interrupted by signal traces.

Refer to the EVM design and more information in the *[BQ25960EVM \(BMS041\) Evaluation Module User's Guide](https://www.ti.com/lit/pdf/SLUUCF7)* for the recommended component placement with trace and via locations.

12.2 Layout Example

Figure 12-1. BQ25960 Layout Example

13 Device and Documentation Support

13.1 Device Support

13.1.1 Third-Party Products Disclaimer

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13.2 Documentation Support

13.2.1 Related Documentation

For related documentation see the following:

• *[BQ25960EVM \(BMS041\) Evaluation Module User's Guide](https://www.ti.com/lit/pdf/SLUUCF7)*

13.3 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on [ti.com.](https://www.ti.com) Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

13.4 Support Resources

TI E2E™ [support forums](https://e2e.ti.com) are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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13.5 Trademarks

TI E2E™ is a trademark of Texas Instruments. All trademarks are the property of their respective owners.

13.6 Electrostatic Discharge Caution

This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

13.7 Glossary

[TI Glossary](https://www.ti.com/lit/pdf/SLYZ022) This glossary lists and explains terms, acronyms, and definitions.

14 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

PACKAGING INFORMATION

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures. "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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TEXAS

TAPE AND REEL INFORMATION

ISTRUMENTS

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

PACKAGE MATERIALS INFORMATION

www.ti.com 26-Dec-2022

*All dimensions are nominal

PACKAGE OUTLINE

YBG0036 DSBGA - 0.5 mm max height

DIE SIZE BALL GRID ARRAY

NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.

EXAMPLE BOARD LAYOUT

YBG0036 DSBGA - 0.5 mm max height

DIE SIZE BALL GRID ARRAY

NOTES: (continued)

3. Final dimensions may vary due to manufacturing tolerance considerations and also routing constraints. See Texas Instruments Literature No. SNVA009 (www.ti.com/lit/snva009).

EXAMPLE STENCIL DESIGN

YBG0036 DSBGA - 0.5 mm max height

DIE SIZE BALL GRID ARRAY

NOTES: (continued)

4. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release.

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